

1. Record Nr.	UNINA9910830202703321
Titolo	X-rays and materials [[electronic resource] /] / edited by Philippe Goudeau, Rene Guinebretiere
Pubbl/distr/stampa	Hoboken, N.J., : ISTE/Wiley, 2012
ISBN	1-118-56288-7 1-283-94140-6 1-118-56293-3
Descrizione fisica	1 online resource (240 p.)
Collana	ISTE
Altri autori (Persone)	GoudeauPhilippe GuinebretiereRene
Disciplina	620.11272
Soggetti	Materials - Analysis X-ray microanalysis X-rays - Diffraction X-ray spectroscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Cover; X-Rays and Materials; Title Page; Copyright Page; Table of Contents; Preface; Chapter 1. Synchrotron Radiation: Instrumentation in Condensed Matter; 1.1. Introduction; 1.2. Light sources in the storage ring; 1.2.1. Bending magnets; 1.2.2. Insertion devices; 1.2.2.1. Wigglers; 1.2.2.2. Undulators; 1.3. Emittance and brilliance of a source; 1.4. X-ray diffraction with synchrotron radiation; 1.4.1. Angle-dispersive diffraction; 1.4.2. Energy dispersive diffraction; 1.5. X-ray absorption spectroscopy using synchrotron radiation; 1.5.1. X-ray absorption spectroscopy 1.5.2. Energy-scanned X-ray absorption spectroscopy1.5.3. Energy dispersive X-ray absorption spectroscopy; 1.6. SAMBA: the X-ray absorption spectroscopy beam line of SOLEIL for 4-40 keV; 1.7. The DIFFABS beam line; 1.7.1. Description of the beam line; 1.7.2. Examples of use of the DIFFABS beam line; 1.8. CRISTAL beam line; 1.8.1. Beam line optics; 1.8.2. Diffractometers; 1.8.3. Sample environments; 1.9. The SOLEIL ODE line for dispersive EXAFS; 1.9.1. Optics of the ODE line; 1.9.2. Magnetic circular dichroism

1.9.3. X-ray absorption spectroscopy under extreme pressure and/or temperature conditions; 1.10. Conclusion; 1.11. Bibliography; Chapter 2. Nanoparticle Characterization using Central X-ray Diffraction; 2.1. Introduction; 2.2. Definition of scattered intensity; 2.3. Invariance principle; 2.3.1. General case; 2.3.2. Isotropic systems; 2.3.3. Multi-level systems; 2.4. Behavior for large q : the Porod regime; 2.5. Particle-based systems; 2.5.1. Definition of form factor; 2.5.2. Introduction to the structure factor; 2.5.3. Intensity behavior at small q : the Guinier regime; 2.5.4. Volume measurements; 2.5.5. Some well-known form factors; 2.5.6. Polyhedral particles; 2.5.6.1. Form factor of a polyhedron; 2.5.6.2. Comparison between different polyhedra with cylindrical and spherical forms; 2.6. An absolute scale for measuring particle numbers; 2.7. Conclusion; 2.8. Bibliography; Chapter 3. X-ray Diffraction for Structural Studies of Carbon Nanotubes and their Insertion Compounds; 3.1. Introduction; 3.1.1. Introduction to carbon nanotubes; 3.1.2. Uses of X-ray scattering for studies of carbon nanotubes; 3.2. Single-walled carbon nanotubes; 3.2.1. Calculation of a powder diffraction diagram; 3.2.1.1. Individual nanotubes; 3.2.1.2. Bundle structure; 3.2.1.3. Inclusion of a distribution of nanotube diameters; 3.2.1.4. Effects of nanotube length; 3.2.2. Analysis of experimental scattering diagrams; 3.3. Multi-walled carbon nanotubes; 3.3.1. Calculation of powder diffraction diagrams for a powder of individual multi-walled nanotubes; 3.3.2. Analysis of an experimental diffraction diagram; 3.4. Hybrid nanotubes; 3.4.1. Peapods; 3.4.2. Ion insertion into nanotubes; 3.5. Textured powder samples; 3.5.1. Quantification of nanotube orientation; 3.5.2. Separation of diffraction components in hybrid nanotubes

Sommario/riassunto

This book presents reviews of various aspects of radiation/matter interactions, be these instrumental developments, the application of the study of the interaction of X-rays and materials to a particular scientific field, or specific methodological approaches. The overall aim of the book is to provide reference summaries for a range of specific subject areas within a pedagogical framework. Each chapter is written by an author who is well known within their field and who has delivered an invited lecture on their subject area as part of the "RX2009 - X-rays and Materials" colloqui
